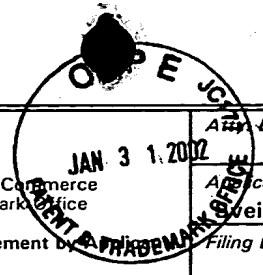


attach to #5

B/O Form PTO-1449		App Docket Number <b>JEK/BEU/OLAFSSON</b>	Serial Number <b>09/670,028</b>
U.S. Department of Commerce Patent and Trademark Office		Applicant <b>Sveinn OLAFSSON</b>	
Information Disclosure Statement by Applicant		Filing Date <b>September 26, 2000</b>	Group <b>1762</b>



**U.S. Patent Documents**

Examiner Initial	Document Number	Date	Patentee/Applicant	Class	Subclass	Filing Date if Appropriate
<i>[Signature]</i>	4566937	1/86	Pitts			
	5534311	7/96	Shaw et al			
	6261421	7/01	Meunier et al			
	5509843	4/96	Akama			
	5352330	10/94	Wallace			
	5015323	5/91	Gallagher			
	5038322	8/91	Van Loenen			
	4343993	8/82	Binnig et al			
	5043578	8/91	Guethner et al			
	4896044	1/90	Li et al			
<i>[Signature]</i>	5047649	9/91	Hodgson et al			



**Foreign Patent Documents**

Examiner Initial	Document Number	Publication Date	Country/Agency	Class	Subclass	Translation	
						Yes	No

**Other Documents (Including Author, Title, Date, Pertinent Pages, Place of Publication, Etc.)**


Examiner <i>[Signature]</i>	Date Considered <i>9/16/02</i>
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EXAMINER: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; Draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

attach to #4

B/O Form PTO-1449  U.S. Department of Commerce Patent and Trademark Office  Information Disclosure Statement by Applicant	Atty. Docket Number <b>JEK/BEU/OLAFSSON</b>	Serial Number <b>09/670,028</b>
	Applicant <b>Sveinn OLAFSSON</b>	
	Filing Date <b>September 26, 2000</b>	<b>1762</b>

U.S. Patent Documents

Examiner Initial	Document Number	Date	Patentee/Applicant	Class	Subclass	Filing Date if Appropriate
MJP	3,663,788	05/1972	INOUE			
	3,713,213	01/1973	CRANSTON			
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Foreign Patent Documents

Examiner Initial	Document Number	Publication Date	Country/Agency	Class	Subclass	Translation	
						Yes	No

Other Documents (Including Author, Title, Date, Pertinent Pages, Place of Publication, Etc.)

MJP	Marchand, H., et al., <u>Structural and optical properties of GaN laterally overgrown on Si(111) by metalorganic chemical vapor deposition using an AlN buffer layer</u> , pp. 1-10, MRS Internet J. Nitride Semicond. Res. 4, 2 (1999). <i>(no month given, but after March 10<sup>th</sup>)</i>
MJP	Van der Stricht, W., et al., <u>Study of GaN films grown by metalorganic chemical vapour deposition</u> , pp. 1-6, MRS Internet J. Nitride Semicond. Res. Vol. 1, Art. 3 (1996). <i>(month not given, but after Aug 5<sup>th</sup>)</i>
MJP	Marchand, H., et al., <u>Fast Lateral Epitaxial Overgrowth of Gallium Nitride by Metalorganic Chemical Vapor Deposition Using a Two-Step Process</u> , pp. 1-6, MRS Internet J. Nitride Semicond. Res. 4S1, G4.5 (1999). <i>no month</i>
MJP	Runge, Keith, et al., <u>Shock and Pressure Wave Propagation in Nano-fluidic Systems</u> , Abstract, Sixth Foresight Conference on Molecular Nanotechnology (1998). <i>no month</i>

Examiner <i>Michael Padgett</i>	Date Considered <i>9/16/02</i>
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